

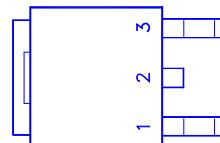
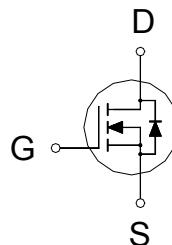
**NIKO-SEM****N-Channel Enhancement Mode  
Field Effect Transistor****PB210BD**

TO-252

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
100V	230m $\Omega$	10A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	10	A
		6	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	40	
Avalanche Current	$I_{AS}$	18	
Avalanche Energy	$E_{AS}$	16.5	mJ
Power Dissipation	$P_D$	41	W
		17	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	3	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	2	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80V, V_{GS} = 0V$			1	
		$V_{DS} = 80V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			10	$\mu\text{A}$
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	40			A

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Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 6A$	191	230	$m\Omega$
		$V_{GS} = 5V, I_D = 6A$	203	240	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 6A$	10		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	802	1002	$pF$
Output Capacitance	$C_{oss}$		80	100	
Reverse Transfer Capacitance	$C_{rss}$		41	51	
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	2.5	3.1	$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = 50V, V_{GS} = 10V,$ $I_D = 6A$	15		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		2		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		4		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 50V,$ $I_D \approx 6A, V_{GS} = 10V, R_{GS} = 6\Omega$	16		$nS$
Rise Time <sup>2</sup>	$t_r$		330		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		39		
Fall Time <sup>2</sup>	$t_f$		111		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>					
Continuous Current	$I_S$			10	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 6A, V_{GS} = 0V$		1.4	V
Reverse Recovery Time	$t_{rr}$	$I_F = 6A, dI/dt=500A/\mu s$	75		$nS$
Reverse Recovery Charge	$Q_{rr}$		0.17		$nC$

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

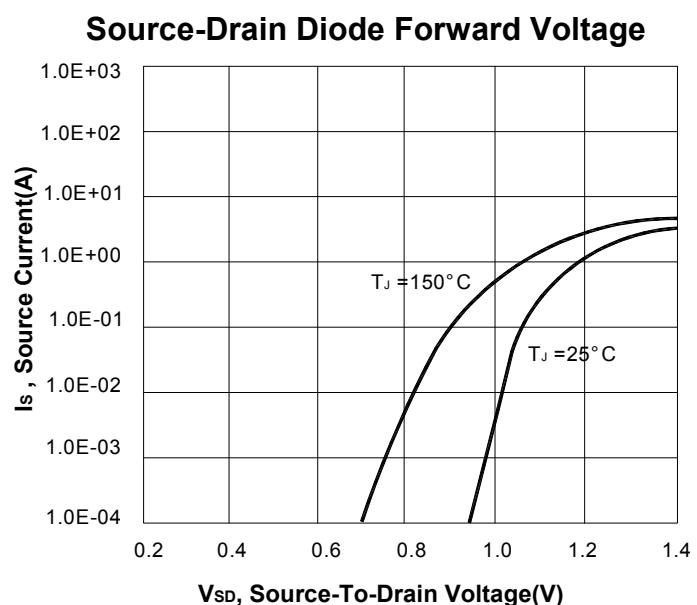
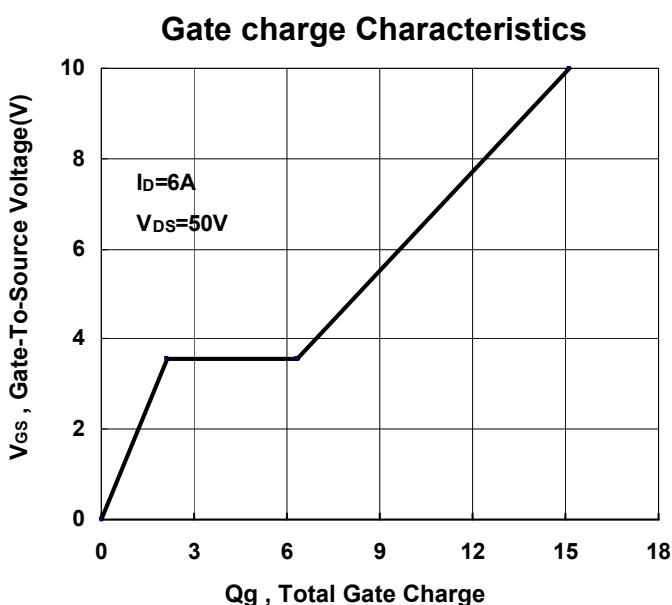
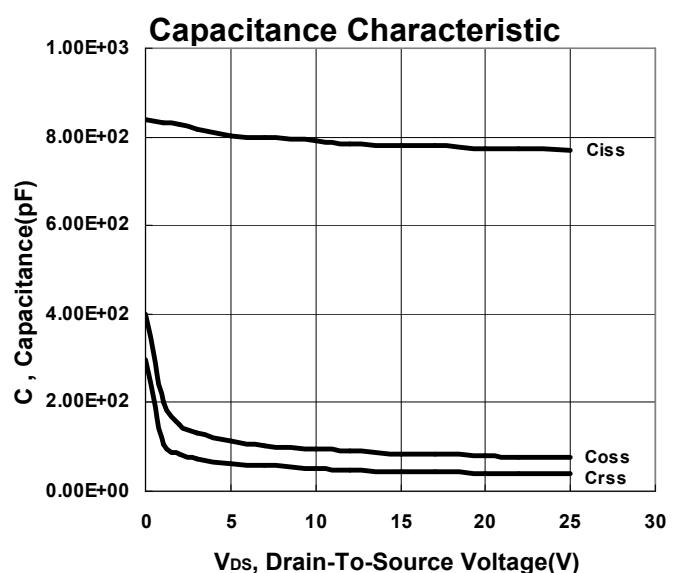
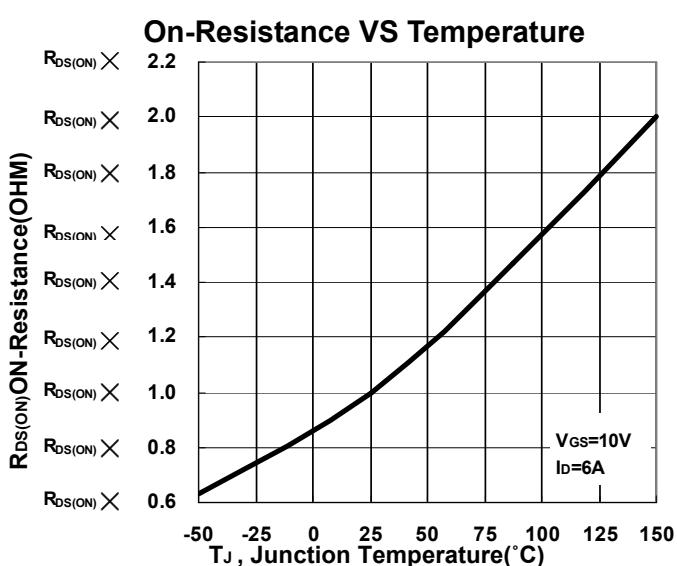
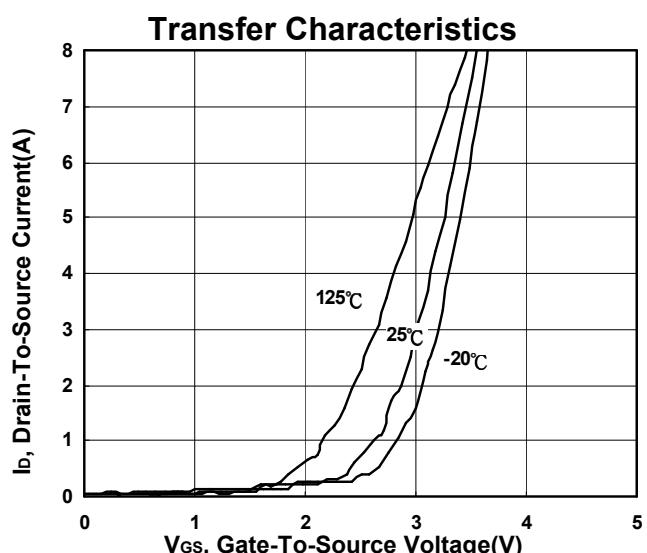
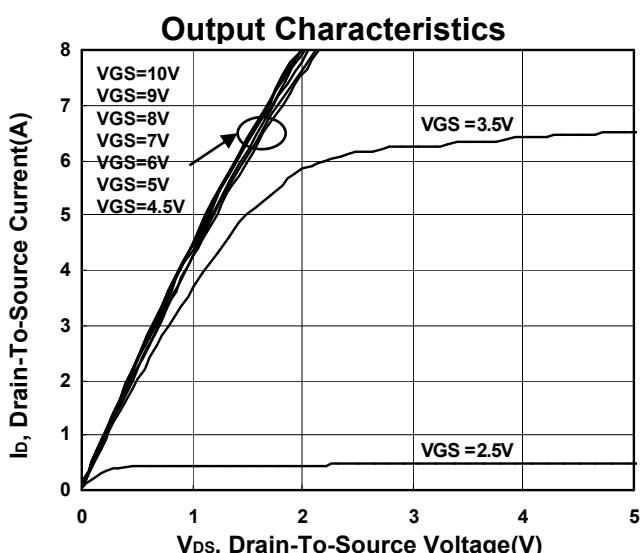
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